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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Applicant: OKUBO et al.	
Appln. No.: 10/544,178	
Filing Date: April 24, 2006	
Examiner: MOORE, W.	Group Art Unit: 2826

Date: January 5, 2010 Page 1 of 1

U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
	AR 5,770,861	06-23-1998	Hirose et al.			
	BR					
	CR					
	DR					
	ER					
	FR					
	GR					
	HR					
	IR					
	JR					
	KR					
	LR					
	MR					
	NR					

FOREIGN PATENT DOCUMENTS

	Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract		Translation Readily Available	
					Enclosed	No	Enclose	No
	OR							
	PR							
	QR							
	RR							
	SR							
	TR							

OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

UR	Inkon B J et al.: "Subsurface nanoindentation deformation of Cu-Al multilayers mapped in 3D by focused ion beam microscopy," Journal of Microscopy, vol. 201, pt. 2, February 2001, pp. 256-269			X
VR	Dunn D N et al.: "Reconstruction of three-dimensional chemistry and geometry using focused ion beam microscopy," Applied Science Letters, vol. 75, number 21, November 22, 1999, pages 3414-3416			X
WR	Sakamoto T. et al.: "Development of an ion and electron dual focused beam apparatus for three-dimensional microanalysis," Japanese Journal of Applied Physics, vol. 37, no. 4A, April 1998, pages 2051-2056			X
XR	Supplementary European Search Report for European Application Number EP 03 75 6661 dated December 17, 2009			X

Examiner Date Considered:

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.